TOSHIBA CMOS Digital Integrated Circuit Silicon Monolithic

# TC4017BP,TC4017BF

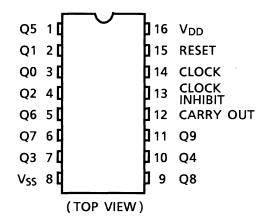
#### TC4017BP/TC4017BF Decade Counter/Divider

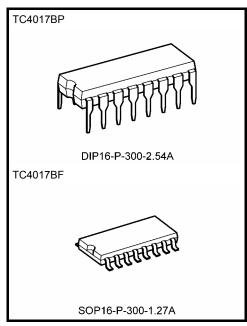
TC4017BP/BF is decimal Johnson counter consisting of 5 stage D-type flip-flop equipped with the decoder to convert the output to decimal

Depending on the number of count pulses fed to CLOCK or CLOCK INHIBIT one output among 10 output lines "Q0" through "Q9" becomes "H" level.

The counter advances its state at rising edge of CLOCK (CLOCK INHIBIT = "L") or falling edge of CLOCK INHIBIT (CLOCK = "H"). RESET input to "H" level resets the counter to Q0 = "H" and Q1 through Q9 = "L" regardless of CLOCK and CLOCK INHIBIT.

### **Pin Assignment**





Weight

DIP16-P-300-2.54A : 1.00 g (typ.) SOP16-P-300-1.27A : 0.18 g (typ.)

### **Truth Table**

	Selected				
CLOCKA	CLOCK INHIBIT∆	RESET	Output		
*	*	Н	Q0		
*	Н	L	Qn (NC)		
L	*	L	Qn (NC)		
	L	L	Qn + 1		
$\neg$	L	L	Qn (NC)		
Н		L	Qn (NC)		
Н		L	Qn + 1		

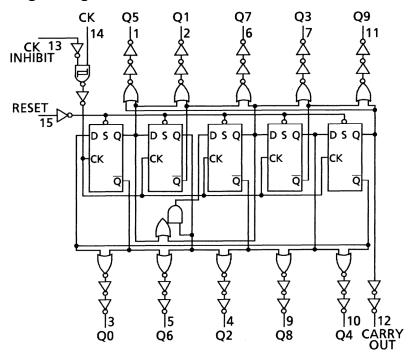
Δ: Level change

\*: Don't care

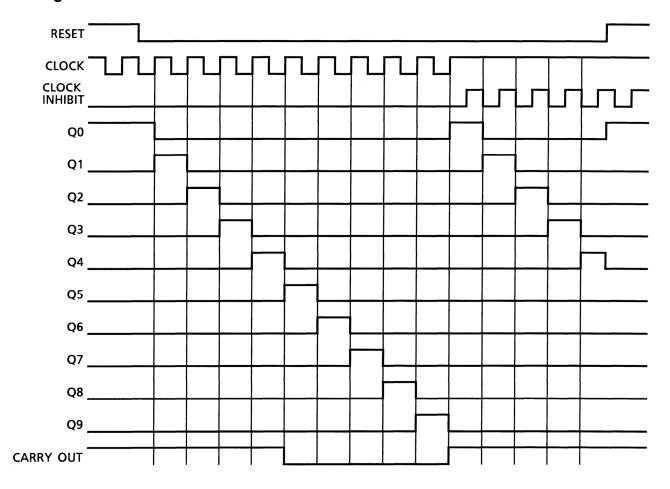
NC: No change carry out 
$$\begin{cases} \text{"H"}.....Q0 \sim Q4 = \text{"H"} \\ \text{"L"}....Q5 \sim Q9 = \text{"H"} \end{cases}$$

2007-10-01

# **Logic Diagram**



# **Timing Chart**



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### **Absolute Maximum Ratings (Note)**

Characteristics	Symbol	Rating	Unit
DC supply voltage	$V_{DD}$	V <sub>SS</sub> - 0.5~V <sub>SS</sub> + 20	V
Input voltage	V <sub>IN</sub>	V <sub>SS</sub> - 0.5~V <sub>DD</sub> + 0.5	٧
Output voltage	V <sub>OUT</sub>	V <sub>SS</sub> - 0.5~V <sub>DD</sub> + 0.5	V
DC input current	I <sub>IN</sub>	±10	mA
Power dissipation	P <sub>D</sub>	300 (DIP)/180 (SOIC)	mW
Operating ambient temperature range	T <sub>opr</sub>	-40~85	°C
Storage temperature range	T <sub>stg</sub>	-65~150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

### Operating Ranges (V<sub>SS</sub> = 0 V) (Note)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
DC supply voltage	$V_{DD}$	_	3	_	18	V
Input voltage	V <sub>IN</sub>		0	_	$V_{DD}$	V

Note: The operating ranges must be maintained to ensure the normal operation of the device. Unused inputs must be tied to either  $V_{DD}$  or  $V_{SS}$ .

# Static Electrical Characteristics ( $V_{SS} = 0 V$ )

Characteristics		Sym-	Test Condition		-40°C		25°C			85°C		11. 2
		bol		V <sub>DD</sub> (V)	Min	Max	Min	Тур.	Max	Min	Max	Unit
_			I <sub>OUT</sub>   < 1 μA	5	4.95	_	4.95	5.00	_	4.95	_	
High-level voltage	output	V <sub>OH</sub>	$V_{IN} = V_{SS}, V_{DD}$	10	9.95	_	9.95	10.00	_	9.95	_	V
			VIN - VSS, VDD	15	14.95	_	14.95	15.00	_	14.95	_	
<b>l</b>			I <sub>OUT</sub>   < 1 μA	5	_	0.05	_	0.00	0.05	_	0.05	
Low-level voltage	output	V <sub>OL</sub>	$V_{IN} = V_{SS}, V_{DD}$	10	_	0.05	_	0.00	0.05		0.05	V
			*IN *33, *DD	15	_	0.05	_	0.00	0.05	—	0.05	
			V <sub>OH</sub> = 4.6 V	5	-0.61	_	-0.51	-1.0	_	-0.42	_	
			V <sub>OH</sub> = 2.5 V	5	-2.50	_	-2.10	-4.0	_	-1.70	_	mA
Output hig	gh current	IOH	V <sub>OH</sub> = 9.5 V	10	-1.50	_	-1.30	-2.2	_	-1.10	_	
			V <sub>OH</sub> = 13.5 V	15	-4.00	_	-3.40	-9.0	_	-2.80	_	
			$V_{IN} = V_{SS}, V_{DD}$									
		l <sub>OL</sub>	V <sub>OL</sub> = 0.4 V	5	0.61	_	0.51	1.5	_	0.42	_	mA
Output lov	v current		V <sub>OL</sub> = 0.5 V	10	1.50	_	1.30	3.8	_	1.10	_	
			V <sub>OL</sub> = 1.5 V	15	4.00	_	3.40	15.0	_	2.80	_	
			$V_{IN} = V_{SS}, V_{DD}$									
		VIH	V <sub>OUT</sub> = 0.5 V, 4.5 V	5	3.5	_	3.5	2.75	_	3.5	_	V
Input high	voltage		$V_{OUT} = 1.0 \text{ V}, 9.0 \text{ V}$	10	7.0	_	7.0	5.50	_	7.0	_	
putg	romago	* " "	V <sub>OUT</sub> = 1.5 V, 13.5 V	15	11.0	_	11.0	8.25	_	11.0	_	
			I <sub>OUT</sub>   < 1 μA									
			V <sub>OUT</sub> = 0.5 V, 4.5 V	5	_	1.5	_	2.25	1.5	_	1.5	
Input low voltage		VIL	$V_{OUT} = 1.0 \text{ V}, 9.0 \text{ V}$	10	_	3.0	_	4.50	3.0	_	3.0	V
		, 1	V <sub>OUT</sub> = 1.5 V, 13.5 V	15	_	4.0	_	6.75	4.0	_	4.0	
			I <sub>OUT</sub>   < 1 μA									
Input	"H" level	lıH	V <sub>IH</sub> = 18 V	18	_	0.1	_	10 <sup>-5</sup>	0.1	—	1.0	μА
current	"L" level	Iμ	V <sub>IL</sub> = 0 V	18	_	-0.1	_	-10 <sup>-5</sup>	-0.1		-1.0	P44 1
Outre	h a committee		$V_{IN} = V_{SS}, V_{DD}$	5	_	5	_	0.005	5	_	150	
Quiescent	Quiescent supply current		VIN = VSS, VDD (Note)	10	_	10	_	0.010	10	_	300	μА
			(.1010)	15	_	15	_	0.015	20	_	600	

Note: All valid input combinations.

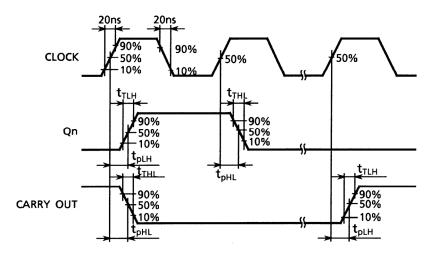
# Dynamic Electrical Characteristics (Ta = 25°C, $V_{SS}$ = 0 V, $C_L$ = 50 pF)

Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit	
Characteristics	Symbol		V <sub>DD</sub> (V)	IVIIII	τyp.	IVIAX	Offic
Output transition time			5	_	80	200	
(low to high)	t <sub>TLH</sub>	_	10	_	50	100	ns
(low to high)			15	_	40	80	
Output transition time			5	_	80	200	
(high to low)	t <sub>THL</sub>	_	10	_	50	100	ns
(High to low)			15	_	40	80	
Propagation delay time	4		5	_	325	650	
(CLOCK-Qn)	t <sub>pLH</sub>	_	10	_	135	270	ns
(CLOCK-QII)	t <sub>pHL</sub>		15	_	85	170	
Decreasion delevitime	4		5	_	280	600	
Propagation delay time	t <sub>pLH</sub>	_	10	_	110	250	ns
(CLOCK-CARRY OUT)	t <sub>pHL</sub>		15	_	75	160	
Propagation delay time	4		5	_	265	530	
RESET-Qn	t <sub>pLH</sub>	_	10	_	115	230	ns
RESET-CARRY OUT	t <sub>pHL</sub>		15	_	85	170	
	f <sub>CL</sub>	_	5	2.5	6.0	_	
Max clock frequency			10	5.0	12.0	_	MHz
			15	6.7	13.5	_	
	tw	_	5	_	85	200	ns
Min clock pulse width			10	_	40	90	
			15	_	35	60	
			5	_	50	260	
Min pulse width	t <sub>WH</sub>	_	10	_	20	110	ns
(RESET)			15	_	15	60	
			5				
Max clock rise time	t <sub>rCL</sub>	_	10		No limit		μS
Max clock fall time	t <sub>fCL</sub>		15				
			5	_	30	230	
Min set-up time	tsu	_	10	_	15	100	ns
(CLOCK INHIBIT-CLOCK)			15	_	10	70	
			5	_	-55	400	
Min removal time	t <sub>rem</sub>	_	10	_	-20	275	ns
(RESET-CLOCK)			15	_	-15	150	
Input capacitance	C <sub>IN</sub>	_		_	5	7.5	pF

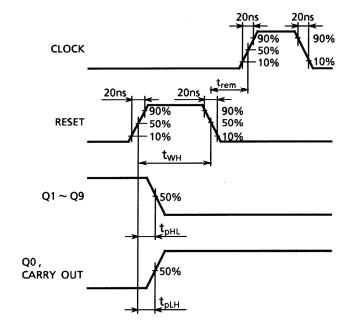
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### **Waveforms for Measurement of Dynamic Characteristics**

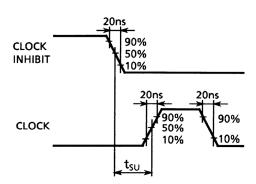
### Waveform 1



#### Waveform 2

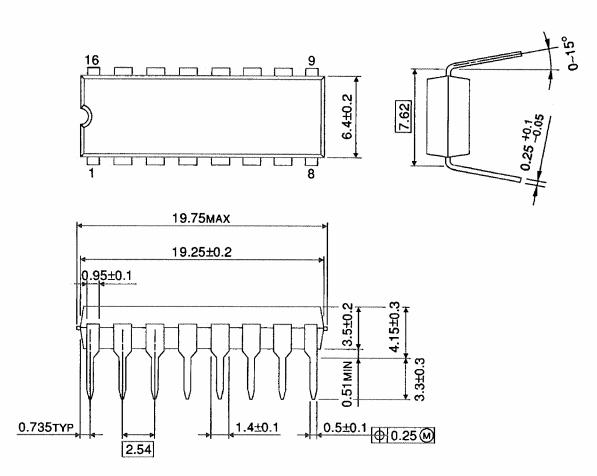


### Waveform 3



# **Package Dimensions**

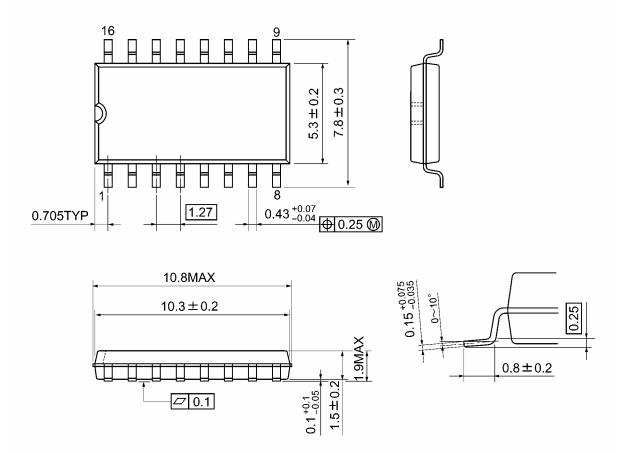
DIP16-P-300-2.54A Unit: mm



Weight: 1.00 g (typ.)

# **Package Dimensions**

SOP16-P-300-1.27A Unit: mm



Weight: 0.18 g (typ.)

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20070701-EN GENERAL

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